

Dual-gate MOS-FET

BF1100WR

FEATURES

- Specially designed for use at 9 to 12 V supply voltage
- Short channel transistor with high forward transfer admittance to input capacitance ratio
- Low noise gain controlled amplifier up to 1 GHz
- Superior cross-modulation performance during AGC.

APPLICATIONS

- VHF and UHF applications such as television tuners and professional communications equipment.

DESCRIPTION

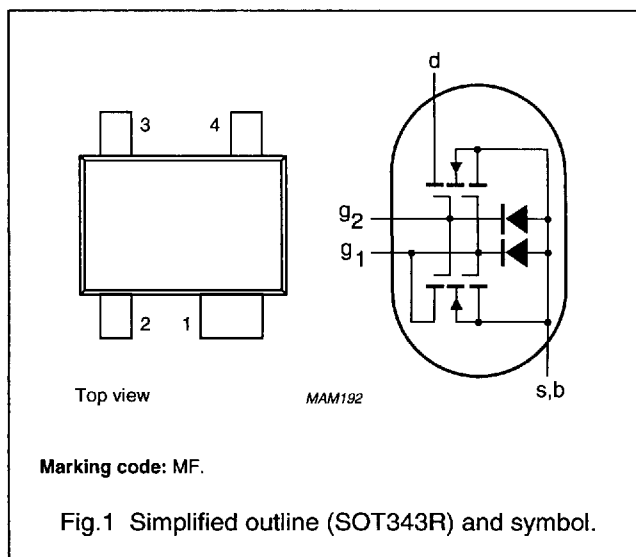
Enhancement type field-effect transistor in a plastic microminiature SOT343R package. The transistor consists of an amplifier MOS-FET with source and substrate interconnected and an internal bias circuit to ensure good cross-modulation performance during AGC.

CAUTION

The device is supplied in an antistatic package. The gate-source input must be protected against static discharge during transport or handling.

PINNING

PIN	SYMBOL	DESCRIPTION
1	s, b	source
2	d	drain
3	g_2	gate 2
4	g_1	gate 1



QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{DS}	drain-source voltage		—	—	14	V
I_D	drain current		—	—	30	mA
P_{tot}	total power dissipation		—	—	280	mW
T_j	operating junction temperature		—	—	150	°C
$ y_{fs} $	forward transfer admittance		24	28	33	mS
C_{ig1-s}	input capacitance at gate 1		—	2.2	2.6	pF
C_{rs}	reverse transfer capacitance	$f = 1 \text{ MHz}$	—	25	35	fF
F	noise figure	$f = 800 \text{ MHz}$	—	2	—	dB

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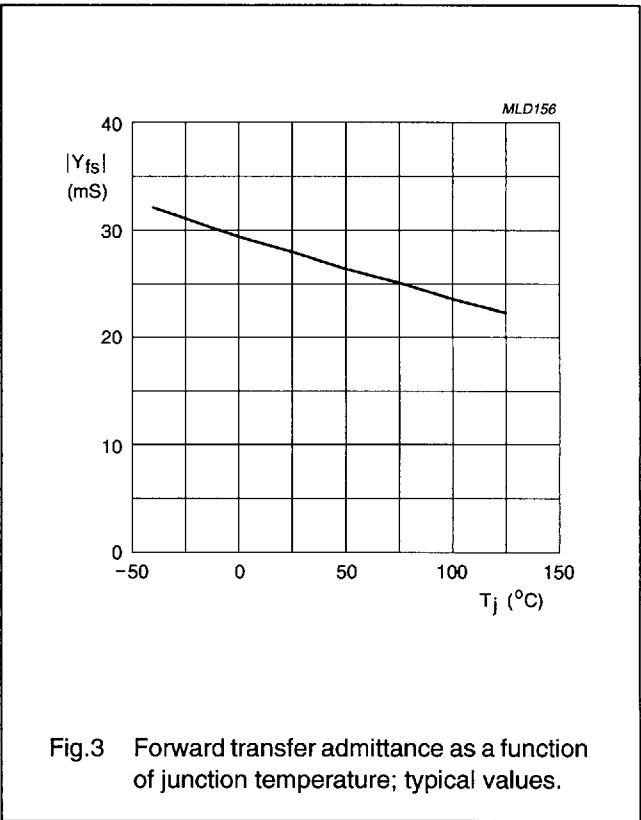
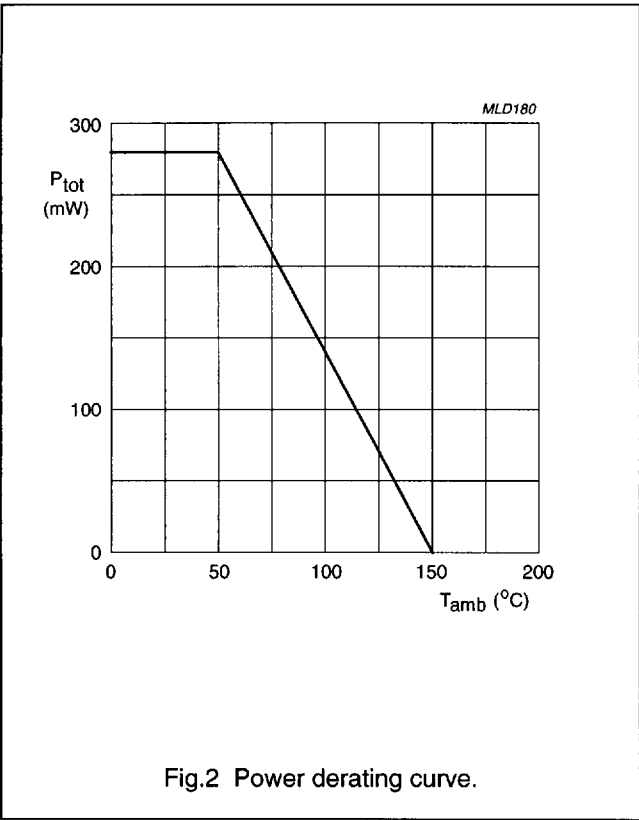
LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	drain-source voltage		–	14	V
I_D	drain current		–	30	mA
I_{G1}	gate 1 current		–	± 10	mA
I_{G2}	gate 2 current		–	± 10	mA
P_{tot}	total power dissipation	see Fig.2; up to $T_{amb} = 50\text{ }^{\circ}\text{C}$; note 1	–	280	mW
T_{stg}	storage temperature		–65	+150	$^{\circ}\text{C}$
T_j	operating junction temperature		–	+150	$^{\circ}\text{C}$

Note

- 1. Device mounted on a printed-circuit board.



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THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
$R_{th\ j-a}$	thermal resistance from junction to ambient	note 1	350	K/W
$R_{th\ j-s}$	thermal resistance from junction to soldering point	$T_s = 91\ ^\circ\text{C}$; note 2	210	K/W

Notes

1. Device mounted on a printed-circuit board.
2. T_s is the temperature at the soldering point of the source lead.

STATIC CHARACTERISTICS

 $T_j = 25\ ^\circ\text{C}$; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{(BR)G1-SS}$	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0$; $I_{G1-S} = 1\ \text{mA}$	13.2	20	V
$V_{(BR)G2-SS}$	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0$; $I_{G2-S} = 1\ \text{mA}$	13.2	20	V
$V_{(F)S-G1}$	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0$; $I_{S-G1} = 10\ \text{mA}$	0.5	1.5	V
$V_{(F)S-G2}$	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0$; $I_{S-G2} = 10\ \text{mA}$	0.5	1.5	V
$V_{G1-S(th)}$	gate 1-source threshold voltage	$V_{G2-S} = 4\ \text{V}$; $V_{DS} = 9\ \text{V}$; $I_D = 20\ \mu\text{A}$	0.3	1	V
		$V_{G2-S} = 4\ \text{V}$; $V_{DS} = 12\ \text{V}$; $I_D = 20\ \mu\text{A}$	0.3	1	V
$V_{G2-S(th)}$	gate 2-source threshold voltage	$V_{G1-S} = 4\ \text{V}$; $V_{DS} = 9\ \text{V}$; $I_D = 20\ \mu\text{A}$	0.3	1.2	V
		$V_{G1-S} = 4\ \text{V}$; $V_{DS} = 12\ \text{V}$; $I_D = 20\ \mu\text{A}$	0.3	1.2	V
I_{DSX}	drain-source current	$V_{G2-S} = 4\ \text{V}$; $V_{DS} = 9\ \text{V}$; $R_{G1} = 180\ \text{k}\Omega$; note 1	8	13	mA
		$V_{G2-S} = 4\ \text{V}$; $V_{DS} = 12\ \text{V}$; $R_{G1} = 250\ \text{k}\Omega$; note 2	8	13	mA
I_{G1-SS}	gate 1 cut-off current	$V_{G2-S} = V_{DS} = 0$; $V_{G1-S} = 12\ \text{V}$	–	50	nA
I_{G2-SS}	gate 2 cut-off current	$V_{G1-S} = V_{DS} = 0$; $V_{G2-S} = 12\ \text{V}$	–	50	nA

Notes

1. R_{G1} connects gate 1 to $V_{GG} = 9\ \text{V}$; see Fig.26.
2. R_{G1} connects gate 1 to $V_{GG} = 12\ \text{V}$; see Fig.26.

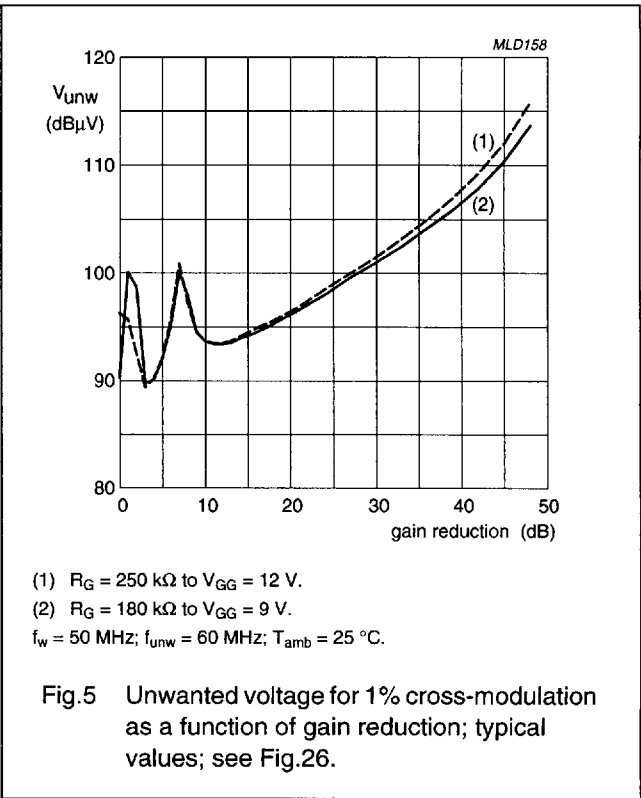
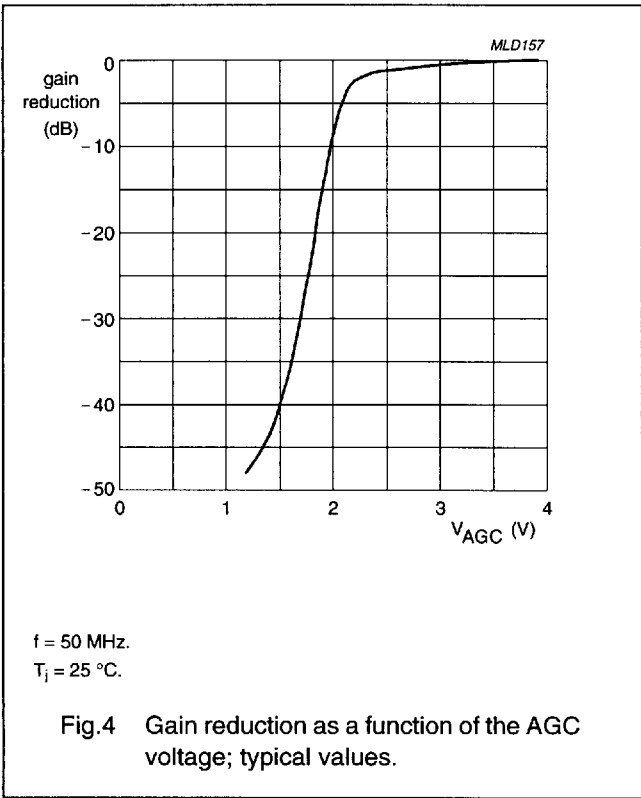
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DYNAMIC CHARACTERISTICS

Common source; $T_{amb} = 25\text{ }^{\circ}\text{C}$; $V_{G2-S} = 4\text{ V}$; $I_D = 10\text{ mA}$; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$ y_{fs} $	forward transfer admittance	pulsed; $T_j = 25\text{ }^{\circ}\text{C}$ $V_{DS} = 9\text{ V}$ $V_{DS} = 12\text{ V}$	24 24	28 28	33 33	mS mS
C_{ig1-s}	input capacitance at gate 1	$f = 1\text{ MHz}$ $V_{DS} = 9\text{ V}$ $V_{DS} = 12\text{ V}$	– –	2.2 2.2	2.6 2.6	pF pF
C_{ig2-s}	input capacitance at gate 2	$f = 1\text{ MHz}$ $V_{DS} = 9\text{ V}$ $V_{DS} = 12\text{ V}$	– –	1.6 1.4	– –	pF pF
C_{os}	drain-source capacitance	$f = 1\text{ MHz}$ $V_{DS} = 9\text{ V}$ $V_{DS} = 12\text{ V}$	– –	1.4 1.1	1.8 1.5	pF pF
C_{rs}	reverse transfer capacitance	$f = 1\text{ MHz}$ $V_{DS} = 9\text{ V}$ $V_{DS} = 12\text{ V}$	– –	25 25	35 35	fF fF
F	noise figure	$f = 800\text{ MHz}$; $G_S = G_{Sopt}$; $B_S = B_{Sopt}$ $V_{DS} = 9\text{ V}$ $V_{DS} = 12\text{ V}$	– –	2 2	2.8 2.8	dB dB



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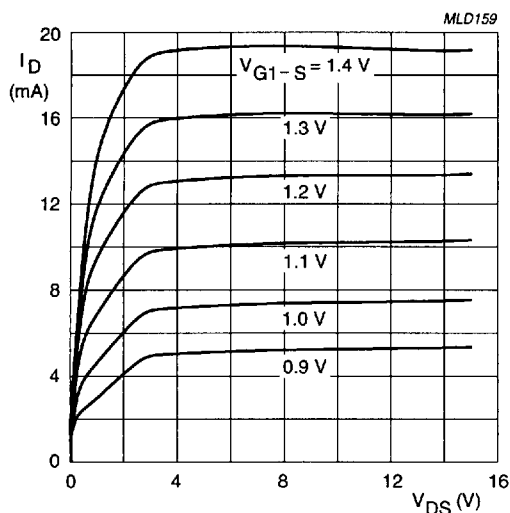


Fig.6 Output characteristics; typical values.

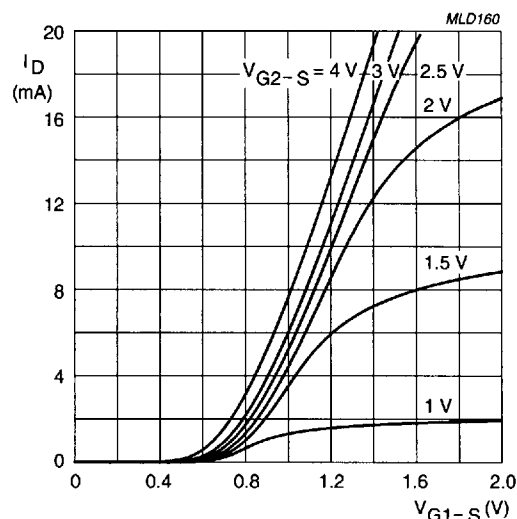


Fig.7 Transfer characteristics; typical values.

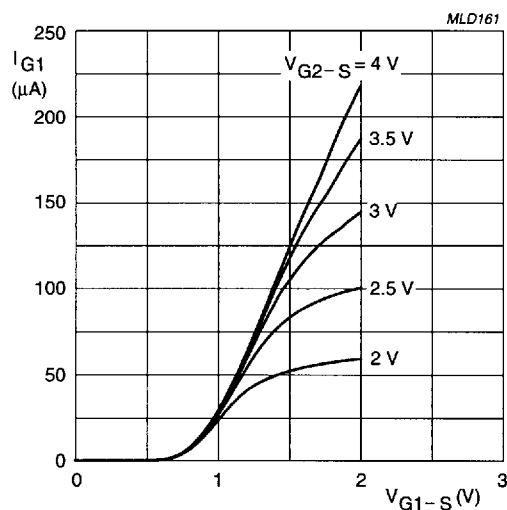


Fig.8 Gate 1 current as a function of gate 1 voltage; typical values.

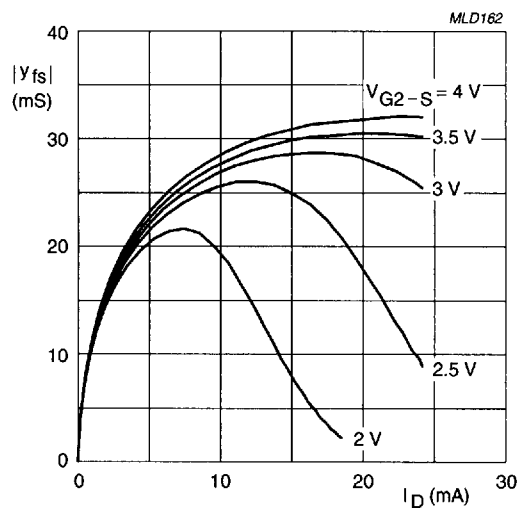
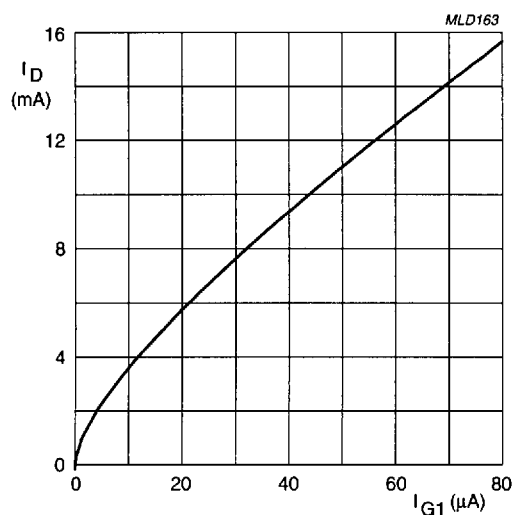


Fig.9 Forward transfer admittance as a function of drain current; typical values.

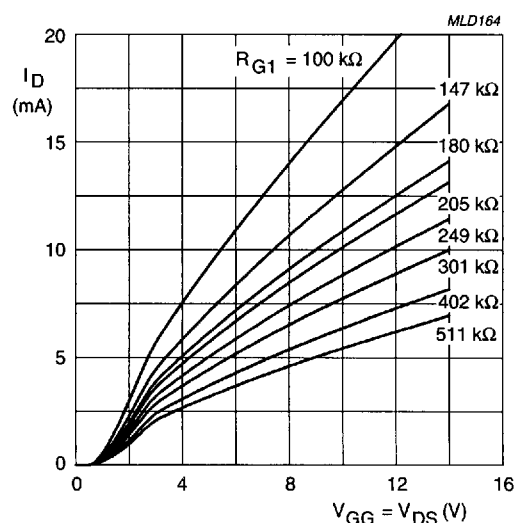
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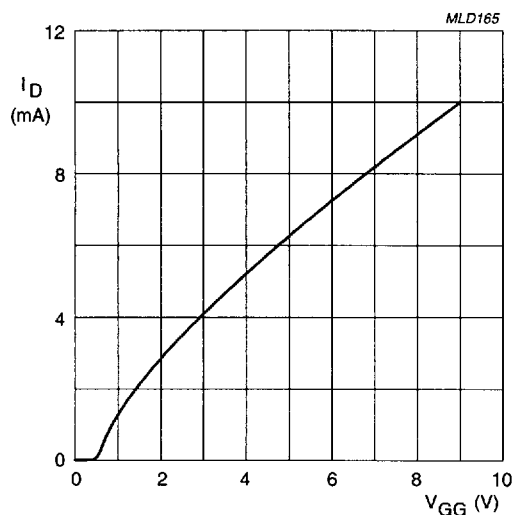
$V_{DS} = 9$ to 12 V.
 $V_{G2-S} = 4$ V.
 $T_J = 25$ °C.

Fig.10 Drain current as a function of gate 1 current; typical values.



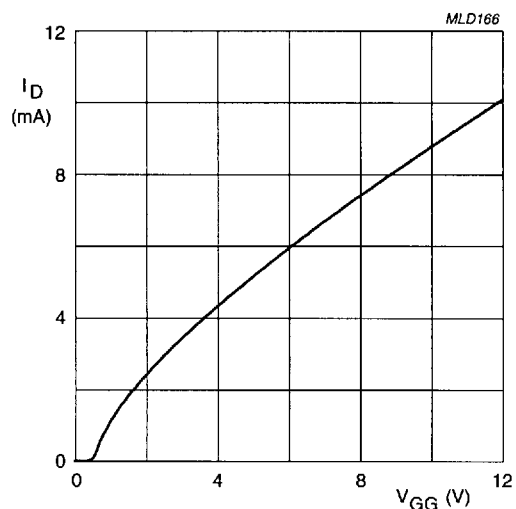
$V_{G2-S} = 4$ V.
 R_{G1} connected to V_{GG} .
 $T_J = 25$ °C.

Fig.11 Drain current as a function of gate 1 supply voltage (= V_{GG}) and drain supply voltage; typical values; see Fig.26.



$V_{DS} = 9$ V; $V_{G2-S} = 4$ V.
 $R_{G1} = 180$ kΩ (connected to V_{GG}); $T_J = 25$ °C.

Fig.12 Drain current as a function of gate 1 voltage (= V_{GG}); typical values; see Fig.26.

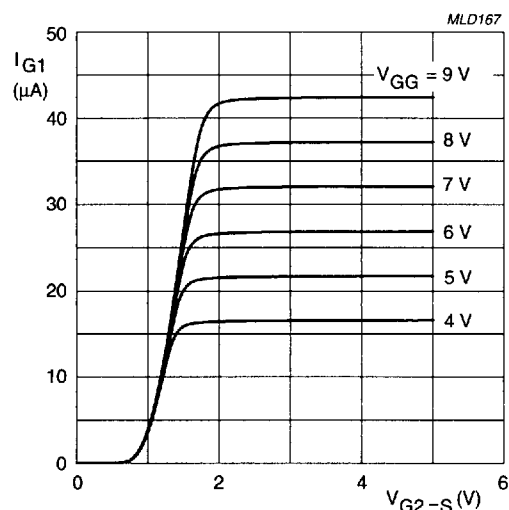


$V_{DS} = 12$ V; $V_{G2-S} = 4$ V.
 $R_{G1} = 250$ kΩ (connected to V_{GG}); $T_J = 25$ °C.

Fig.13 Drain current as a function of gate 1 voltage (= V_{GG}); typical values; see Fig.26.

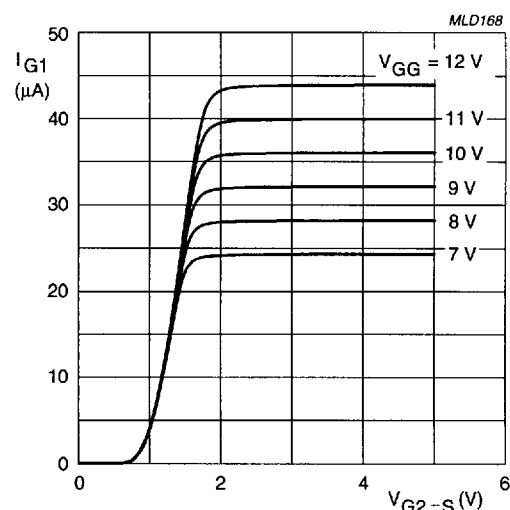
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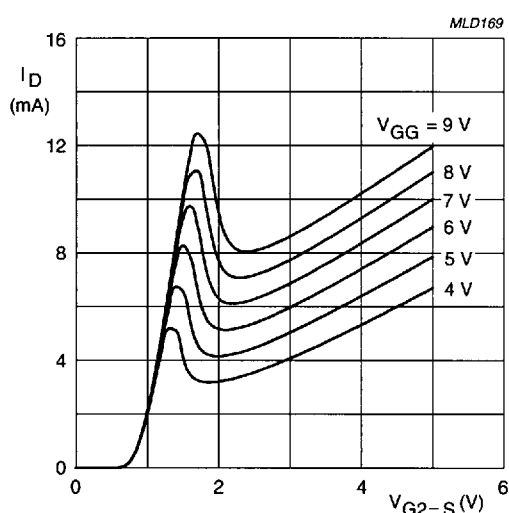
$V_{DS} = 9$ V.
 $R_{G1} = 180$ k Ω (connected to V_{GG}); $T_j = 25$ °C.

Fig.14 Gate 1 current as a function of gate 2 voltage; typical values.



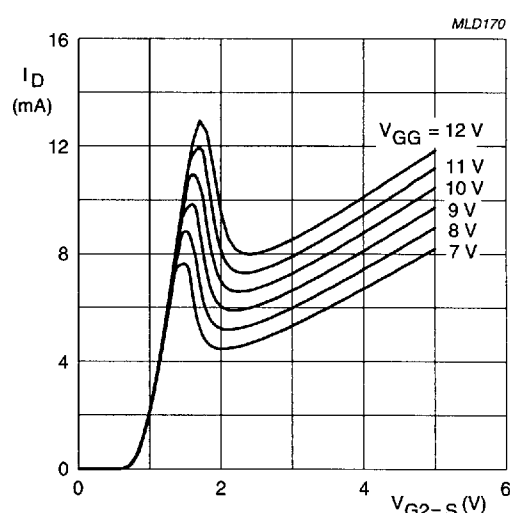
$V_{DS} = 12$ V.
 $R_{G1} = 250$ k Ω (connected to V_{GG}); $T_j = 25$ °C.

Fig.15 Gate 1 current as a function of gate 2 voltage; typical values.



$V_{DS} = 9$ V.
 $R_{G1} = 180$ k Ω (connected to V_{GG}); $T_j = 25$ °C.

Fig.16 Drain current as a function of the gate 2 voltage; typical values; see Fig.26.

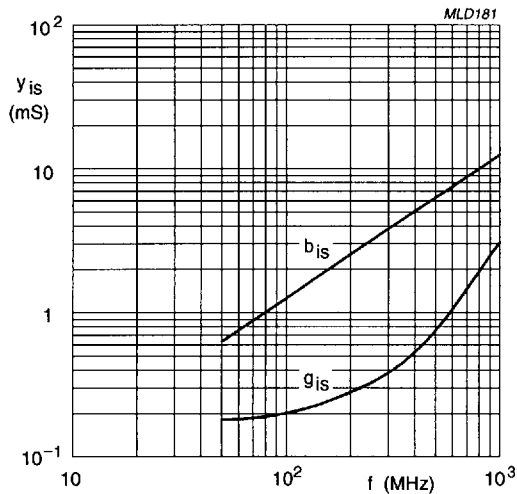


$V_{DS} = 12$ V.
 $R_{G1} = 250$ k Ω (connected to V_{GG}); $T_j = 25$ °C.

Fig.17 Drain current as a function of the gate 2 voltage; typical values; see Fig.26.

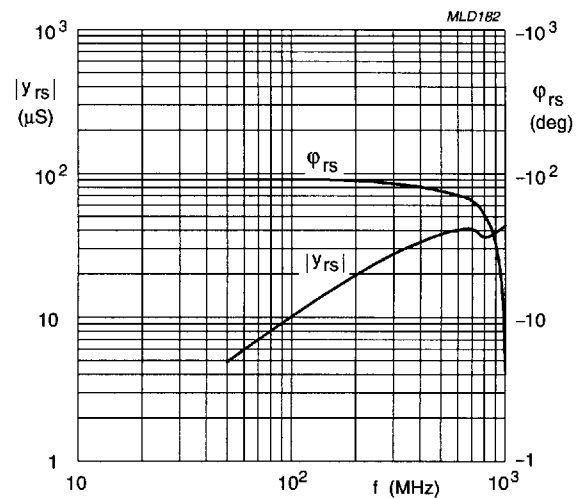
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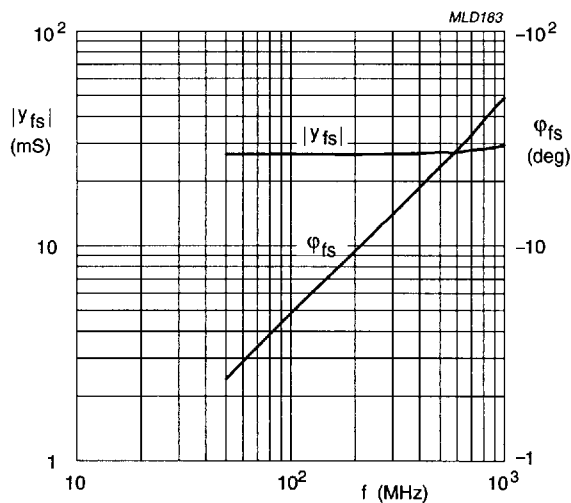
$V_{DS} = 9\text{ V}$; $V_{G2} = 4\text{ V}$.
 $I_D = 10\text{ mA}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.18 Input admittance as a function of frequency; typical values.



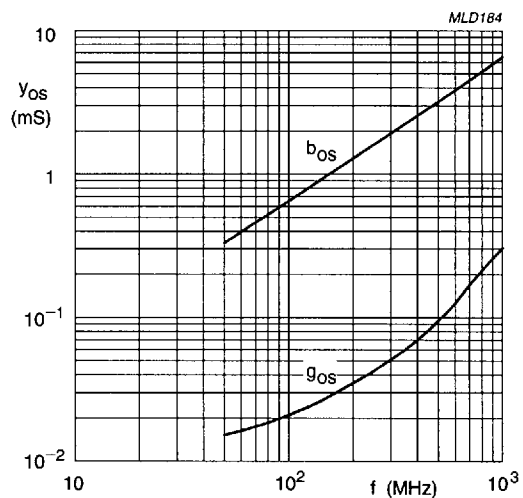
$V_{DS} = 9\text{ V}$; $V_{G2} = 4\text{ V}$.
 $I_D = 10\text{ mA}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.19 Reverse transfer admittance and phase as a function of frequency; typical values.



$V_{DS} = 9\text{ V}$; $V_{G2} = 4\text{ V}$.
 $I_D = 10\text{ mA}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.20 Forward transfer admittance and phase as a function of frequency; typical values.

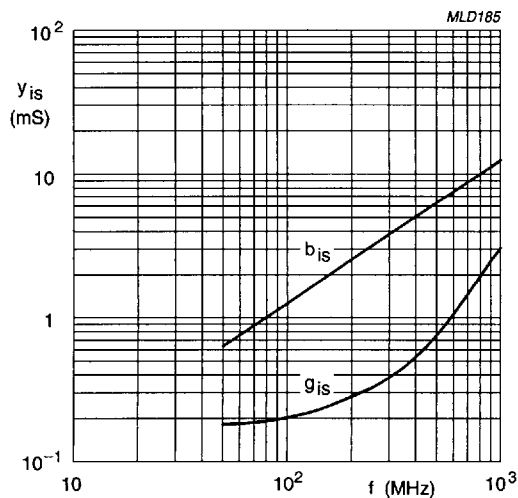


$V_{DS} = 9\text{ V}$; $V_{G2} = 4\text{ V}$.
 $I_D = 10\text{ mA}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.21 Output admittance as a function of frequency; typical values.

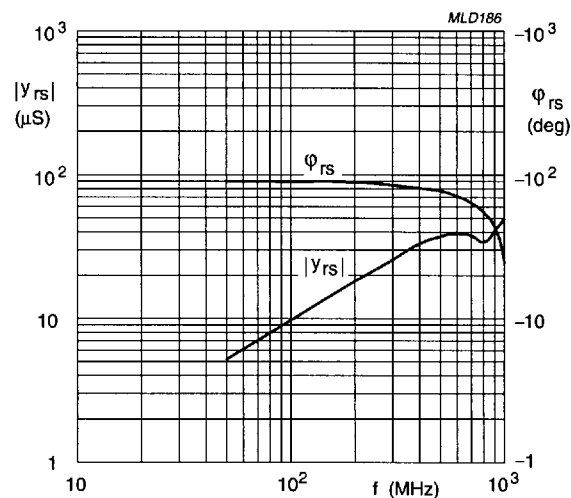
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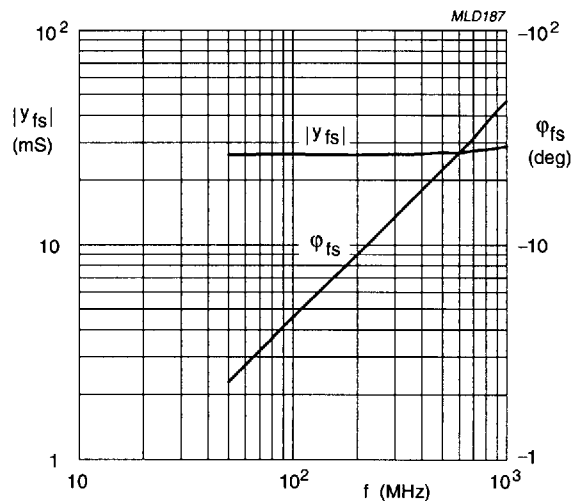
$V_{DS} = 12$ V; $V_{G2} = 4$ V.
 $I_D = 10$ mA; $T_{amb} = 25$ °C.

Fig.22 Input admittance as a function of frequency; typical values.



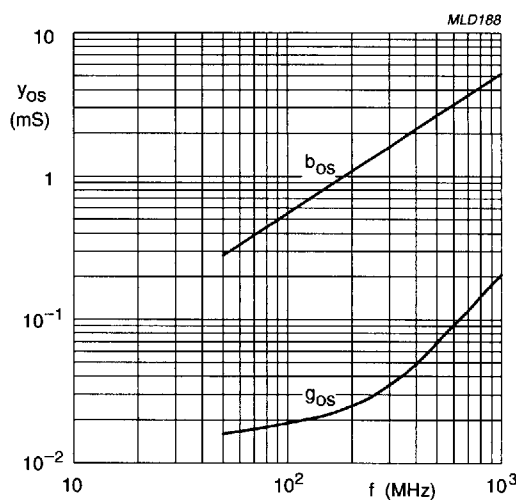
$V_{DS} = 12$ V; $V_{G2} = 4$ V.
 $I_D = 10$ mA; $T_{amb} = 25$ °C.

Fig.23 Reverse transfer admittance and phase as a function of frequency; typical values.



$V_{DS} = 12$ V; $V_{G2} = 4$ V.
 $I_D = 10$ mA; $T_{amb} = 25$ °C.

Fig.24 Forward transfer admittance and phase as a function of frequency; typical values.

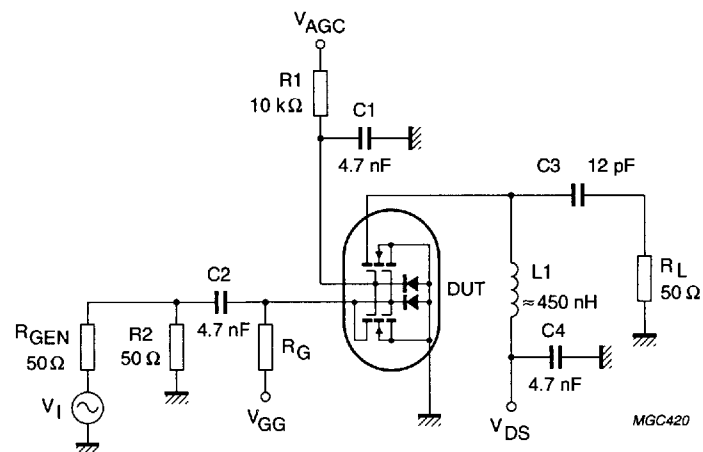


$V_{DS} = 12$ V; $V_{G2} = 4$ V.
 $I_D = 10$ mA; $T_{amb} = 25$ °C.

Fig.25 Output admittance as a function of frequency; typical values.

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For $V_{GG} = V_{DS} = 9$ V, $R_G = 180$ k Ω .

For $V_{GG} = V_{DS} = 12$ V, $R_G = 250$ k Ω .

Fig.26 Cross-modulation test circuit.

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Table 1 Scattering parameters: $V_{DS} = 9\text{ V}$; $V_{G2-S} = 4\text{ V}$; $I_D = 10\text{ mA}$

f (MHz)	S ₁₁		S ₂₁		S ₁₂		S ₂₂	
	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.985	-3.9	2.618	175.1	0.001	137.9	1.000	-1.9
100	0.981	-7.3	2.602	170.5	0.001	80.4	0.999	-4.0
200	0.975	-14.4	2.577	160.7	0.002	74.0	0.995	-7.6
300	0.965	-21.6	2.555	151.6	0.002	79.3	0.994	-11.3
400	0.947	-28.3	2.513	141.8	0.003	80.5	0.992	-15.0
500	0.927	-34.9	2.449	133.4	0.003	82.8	0.988	-18.5
600	0.913	-41.7	2.339	124.6	0.003	78.9	0.984	-22.0
700	0.890	-47.9	2.361	115.4	0.003	80.6	0.982	-25.3
800	0.869	-54.0	2.302	106.4	0.003	93.9	0.979	-28.8
900	0.845	-59.7	2.228	97.6	0.003	104.8	0.976	-32.1
1000	0.823	-65.4	2.167	89.6	0.003	129.3	0.974	-35.5

Table 2 Noise data: $V_{DS} = 9\text{ V}$; $V_{G2-S} = 4\text{ V}$; $I_D = 10\text{ mA}$

f (MHz)	F _{min} (dB)	Γ _{opt}		r _n
		(ratio)	(deg)	
800	2.00	0.67	43.9	0.89

Table 3 Scattering parameters: $V_{DS} = 12\text{ V}$; $V_{G2-S} = 4\text{ V}$; $I_D = 10\text{ mA}$

f (MHz)	S ₁₁		S ₂₁		S ₁₂		S ₂₂	
	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.985	-3.7	2.576	175.3	0.000	125.0	1.000	-1.6
100	0.980	-7.4	2.563	170.9	0.001	111.2	1.000	-3.3
200	0.973	-14.6	2.541	161.6	0.002	83.0	0.997	-6.4
300	0.962	-21.5	2.519	152.9	0.002	85.2	0.996	-9.3
400	0.946	-28.5	2.479	143.5	0.003	79.4	0.995	-12.4
500	0.929	-35.0	2.419	135.5	0.003	78.2	0.991	-15.3
600	0.912	-41.6	2.373	127.2	0.003	80.0	0.989	-18.1
700	0.895	-47.8	2.336	118.7	0.003	83.4	0.987	-20.9
800	0.868	-53.8	2.284	110.0	0.003	91.3	0.985	-23.7
900	0.845	-59.8	2.213	101.6	0.003	95.9	0.983	-26.5
1000	0.823	-65.7	2.160	94.1	0.003	112.2	0.981	-29.3

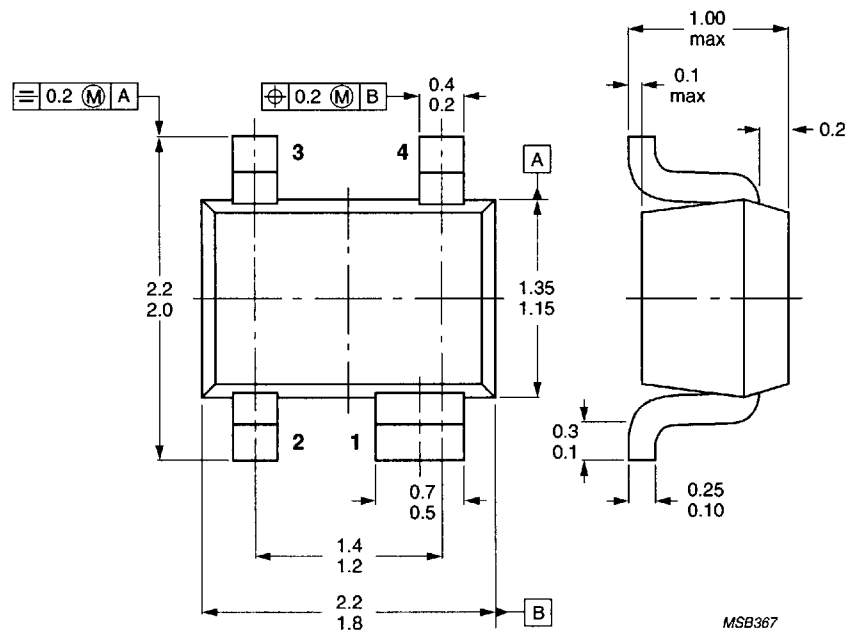
Table 4 Noise data: $V_{DS} = 12\text{ V}$; $V_{G2-S} = 4\text{ V}$; $I_D = 10\text{ mA}$

f (MHz)	F _{min} (dB)	Γ _{opt}		r _n
		(ratio)	(deg)	
800	2.00	0.66	43.3	0.97

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PACKAGE OUTLINE



Dimensions in mm.

Fig.27 SOT343R.